Search Notes		
I IKARA III LA		

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/041,957	TEIG ET AL.	
Examiner	Art Unit	
Binh C. Tat	2825	

SEARCHED			
Class	Subclass	Date	Examiner
716	7-14	8/6/2005	вт

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST SEARCH	8/6/2005	ВТ
1991		